

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S12	91820	predict\$3 and (manufacturing product fabrication)and (yield defect)	US-PGPUB; USPAT; USOCR; DERWENT	OR	ON	2005/10/06 17:42
S13	3643	predict\$3 same (manufacturing product fabrication)same (yield defect)	US-PGPUB; USPAT; USOCR; DERWENT	OR	ON	2005/10/03 14:41
S14	67	predict\$3 same (manufacturing product fabrication)same (yield defect) and "716"/\$.ccls.	US-PGPUB; USPAT; USOCR; DERWENT	OR	ON	2005/10/06 12:44
S15	17	predict\$3 same (manufacturing product fabrication)same (yield defect) and "716"/\$.ccls. and library	US-PGPUB; USPAT; USOCR; DERWENT	OR	ON	2005/10/05 15:39
S16	12	predict\$3 same (manufacturing product fabrication)same (yield defect) and "716"/\$.ccls. and library same (element cell macro)	US-PGPUB; USPAT; USOCR; DERWENT	OR	ON	2005/10/03 14:50
S18	4	predict\$3 and (manufacturing product fabrication) and (yield defect) and library and (element cell macro)and normalization adj2 factor and "716"/\$.ccls.	US-PGPUB; USPAT; USOCR; DERWENT	OR	ON	2005/10/04 18:58
S19	118629	(library or file or database) same (count\$3 or number) same ( normal\$8 or scal\$3 or standard\$3 or averag\$3 or relativ\$5)	US-PGPUB; USPAT; USOCR; DERWENT	OR	ON	2005/10/04 18:19
S20	1410166	yield\$3	US-PGPUB; USPAT; USOCR; DERWENT	OR	ON	2005/10/04 18:20
S21	51767	density same ( defect\$3 or failure or fault)	US-PGPUB; USPAT; USOCR; DERWENT	OR	ON	2005/10/05 19:08
S23	14	S19 and S20 and S21 and "716"/\$.ccls.	US-PGPUB; USPAT; USOCR; DERWENT	OR	ON	2005/10/04 18:31
S24	11	S19 and S20 and S21 and predict\$3 and "716"/\$.ccls.	US-PGPUB; USPAT; USOCR; DERWENT	OR	ON	2005/10/04 18:44
S26	3	S19 and S20 and S21 and predict\$3 and "714"/\$.ccls.	US-PGPUB; USPAT; USOCR; DERWENT	OR	ON	2005/10/04 18:46

S27	13	S19 and S20 and S21 and predict\$3 and "702"/\$.ccls.	US-PGPUB; USPAT; USOCR; DERWENT	OR	ON	2005/10/04 18:46
S28	204	predict\$3 and yield and ( defect\$3 fault failure) and (file or library or database )and (element cell macro)and (normal\$8 or scal\$3 or standard\$3 or averag\$3 or relativ\$5) and "716"/\$.ccls.	US-PGPUB; USPAT; USOCR; DERWENT	OR	ON	2005/10/04 19:02
S29	18	predict\$3 same yield same ( defect\$3 fault failure) and (file or library or database )and (element cell macro)and (normal\$8 or scal\$3 or standard\$3 or averag\$3 or relativ\$5) and "716"/\$.ccls.	US-PGPUB; USPAT; USOCR; DERWENT	OR	ON	2005/10/05 12:54
S30	204	predict\$3 and yield and ( defect\$3 fault failure) and (file or library or database )and (element cell macro)and (normal\$8 or scal\$3 or standard\$3 or averag\$3 or relativ\$5) and "716"/\$.ccls.	US-PGPUB; USPAT; USOCR; DERWENT	OR	ON	2005/10/04 19:31
S31	31	predict\$3 near4 yield and ( defect\$3 fault failure) and (file or library or database )and (element cell macro)and (normal\$8 or scal\$3 or standard\$3 or averag\$3 or relativ\$5) and "716"/\$.ccls.	US-PGPUB; USPAT; USOCR; DERWENT	OR	ON	2005/10/06 12:29
S32	4	predict\$3 near4 yield same ( defect\$3 fault failure) same (file or library or database )and (element cell macro)and (normal\$8 or scal\$3 or standard\$3 or averag\$3 or relativ\$5) and "716"/\$.ccls.	US-PGPUB; USPAT; USOCR; DERWENT CLM	OR	ON	2005/10/04 19:40
S39	172	predict\$3 same yield same ( defect\$3 fault failure) and (file or library or database )and (element cell macro)and (normal\$8 or scal\$3 or standard\$3 or averag\$3 or relativ\$5) and @ad<"20030926"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/05 13:58
S40	72	predict\$3 adj4 yield same ( defect\$3 fault failure) and (file or library or database )and (element cell macro)and (normal\$8 or scal\$3 or standard\$3 or averag\$3 or relativ\$5) and @ad<"20030926"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/05 19:11
S41	17	predict\$3 same (manufacturing product fabrication)same (yield defect) and "716"/\$.ccls. and library	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/05 19:07

S50	3776	predict\$3 same (manufacturing product fabrication)same (yield defect)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/05 19:07
S51	56892	density same ( defect\$3 or failure or fault)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/05 19:08
S52	338	S50 and S51	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/05 19:09
S53	270	S50 and S51 and circuit	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/05 19:09
S54	4	S50 and S51 and circuit adj4 count\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/05 19:10
S55	20	(predict\$3 adj4 yield) and ( defect\$3 fault failure) and (file or library or database )and (element cell macro)and (normal\$8 or scal\$3 or standard\$3 or averag\$3 or relativ\$5) and circuit near5 (count\$3 number\$3)and @ad<"20030926"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/05 19:39
S59	25	(predict\$3 adj4 yield) and (normal\$8 adj4 factor)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/05 19:43
S60	19	(predict\$3 adj4 yield) and (normal\$8 adj4 factor) and @ad<"20030926"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/05 19:43

S72	67	predict\$3 same (manufacturing product fabrication)same (yield defect) and "716"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/06 10:09
S73	3778	predict\$3 same (manufacturing product fabrication)same (yield defect)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/06 10:09
S74	175170	normal\$8 same factor	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/06 10:10
S75	502	S73 and S74	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/06 10:10
S76	43	S73 and S74 and ((circuit element ) adj4 (number\$3 count\$3))and @ad<"20030926"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/06 10:13
S77	25	(predict\$3 adj4 yield) and (normal\$7 adj4 factor)	US-PGPUB; USPAT; USOCR; DERWENT	OR	ON	2005/10/06 12:10
S78	17	(predict\$3 adj4 yield) and (normal\$7 adj4 factor) and defect\$3	US-PGPUB; USPAT; USOCR; DERWENT	OR	ON	2005/10/06 10:23
S79	2	(predict\$3 adj4 yield) and (normal\$7 adj4 factor) and defect\$3 and "700"/\$.ccls.	US-PGPUB; USPAT; USOCR; DERWENT	OR	ON	2005/10/06 10:23
S82	25	(predict\$3 adj4 yield) and (normal\$7 adj4 factor)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/06 10:24

S86	17	(predict\$3 adj4 yield) and (normal\$7 adj4 factor) and defect\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/06 12:18
S88	199	(predict\$3 near4 yield) and ( defect\$3 fault failure) and (file or library or database )and (normal\$8 or scal\$3 or standard\$3 or averag\$3 or relativ\$5) and (( count\$3 number\$3 calculat\$3 comput\$3 evaluat\$3) near4 (element cell macro)) and @ad<"20030926"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/06 12:35
S89	12	(predict\$3 near4 yield) and ( defect\$3 fault failure) and (file or library or database )and (normal\$8 or scal\$3 or standard\$3 or averag\$3 or relativ\$5) and (( count\$3 number\$3 calculat\$3 comput\$3 evaluat\$3) near4 (element cell macro)) and @ad<"20030926" and "716"/\$.cls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/06 12:37
S90	24	(predict\$3 near4 yield) and ( defect\$3 fault failure) and (file or library or database )and (normal\$8 or scal\$3 or standard\$3 or averag\$3 or relativ\$5) and (( count\$3 number\$3 calculat\$3 comput\$3 evaluat\$3) near4 (element cell macro)) and @ad<"20030926" and "700"/\$.cls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/06 12:39
S91	3	(predict\$3 near4 yield) and ( defect\$3 fault failure) and (file or library or database )and (normal\$8 or scal\$3 or standard\$3 or averag\$3 or relativ\$5) and (( count\$3 number\$3 calculat\$3 comput\$3 evaluat\$3) near4 (element cell macro)) and @ad<"20030926" and "714"/\$.cls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/06 12:42
S92	3649	predict\$3 same (manufacturing product fabrication)same (yield defect)	US-PGPUB; USPAT; USOCR; DERWENT	OR	ON	2005/10/06 12:46
S93	9581	normal\$7 adj4 factor	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/06 12:46
S94	49	S92 and S93	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/06 12:45

S96	1443	predict\$3 adj4 yield	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/06 15:53
S97	9581	normal\$7 adj4 factor	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/06 15:54
S98	95479	circuit adj4 count\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/06 15:55
S99	5741	density adj4 defect\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/06 15:55
S10 0	258	S97 and S98	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/06 15:56
S10 1	4	S99 and S100	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/06 16:00
S10 2	3	S96 and S101	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/06 16:04